

# DKT2024 - 53. Deutsche Kristallzüchtungstagung, 6.-8. März 2024, Erlangen

## Mittwoch, 6. März 2024

- 12:00 Registration Open  
12:45 Opening Ceremony

### Production of Compound Semiconductors

- 13:00 S. Eichler, Investigation of low-epd GaAs and InP  
13:30 P. Heimann, CdTe Single Crystals for Photon Counting – A Quantum Leap in CT Medical Imaging  
14:00 R. Eckstein, 30 Jahre Siliziumkarbid-Substrate  
14:30 Coffee Break

### (Ultra) Wide Band Gap Semiconductors

- 15:30 K. Kakimoto, Analysis of impurity and defect distributions during crystal growth of Si, SiC and Ga<sub>2</sub>O<sub>3</sub>  
16:00 T. Straubinger, Growth and preparation of UWBG crystals AlN and Ga<sub>2</sub>O<sub>3</sub> for next generation power electronic  
16:20 G. Lukin, Stress free PVT growth of bulk AlN crystals  
16:40 R. Weingärtner, Inspection of dislocation content in aluminum nitride bulk crystals for quality control in crystal growth: X-ray transmission versus reflection topography  
17:00 J. Ihle, Importance of materials database for modeling of PVT growth process at T > 2000°C  
17:20 K. Schuck-Bühner, Systematic evaluation of contamination behavior originated from innovative spray coated tantalum carbide coating on graphite parts used in SiC epitaxy processes  
17:40 End  
18:10 General Assembly of DGKK

## Donnerstag, 7. März 2024

### Epitaxy of Compound Semiconductors

- 08:30 O. Maßmeyer, MOCVD growth and characterization of 2D materials  
09:00 M. Heukan, Advancements in MOCVD technology for low-cost high-quality III-As/P-based Epitaxy  
09:20 R. Karhu, Comparison between homoepitaxial growth of 4H-SiC on a-plane and 4° off-cut c-plane substrates  
09:40 W. Miller, Kinetic Monte Carlo simulations for study growth kinetics during epitaxial growth  
10:00 Coffee Break

### Solution Growth of Novel Crystals

- 10:40 S. Schwung, KRE(WO<sub>4</sub>)<sub>2</sub> - Eine vielseitige Verbindung für optische Anwendungen  
11:10 H. Abusammala, Single-crystal growth from high-temperature solutions of the hole-doped Mott-insulator Ba<sub>2</sub>CoS<sub>2</sub>  
11:30 C. Krellner, Interplay between 4f and 3d magnetism in LnCo<sub>2</sub>P<sub>2</sub> (Ln = La – Nd) single crystals  
11:50 D.C. Peets, Rouaite, Cu<sub>2</sub>(OH)<sub>3</sub>NO<sub>3</sub>: Growth, Deuteration, Magnetic Phase Diagrams, and Dimensionality of Magnetic Interactions  
12:10 Lunch

### Award Session

- 13:30 DGKK-Young-Scientist Award  
14:00 Award Ceremony of the School Competition  
14:30 DGKK-Award

### Postersession (15:00-16:30)

#### Engineered SiC Substrates

- 16:30 P. Hens, Study on epi performance of engineered SiC substrates in a multi-wafer batch reactor  
16:50 M. Hofmann, Silicon Carbide-on-Insulator and Diamond for Integrated Photonics and Quantum Applications  
17:10 J. Schultheiß, Chemical Vapor Deposition of 3C-SiC on SOI substrates  
17:30 End  
19:15 Conference Dinner,  
Bayerischer Hof, Schuhstraße 31, 91052 Erlangen  
23:00 End

## Freitag, 8. März 2024

### Special Crystals

- 08:40 A. Turchanin, Tailored growth of transition metal dichalcogenides monolayers and their heterostructures  
09:10 M. Dragomir, Single-crystal growth and the role of crystal symmetry on the superconducting properties of Nd-LSCO  
09:40 K. Klemmt, Czochralski growth of Eu-based intermetallic compounds  
10:00 A.-A. Haghighirad, Crystal Growth and Properties of van der Waals Quantum Materials  
10:20 Coffee Break
- ### Advanced Characterization
- 11:00 S. Sandfeld, Data Mining and Deep Learning of Defects in Crystals  
11:30 D. J. Kok, Crystal orientation quantification in less than 10 seconds  
11:50 N. Schüler, Introducing high resolution Surface Photovoltage Spectroscopy (HR-SPS) for investigation of material quality in SiC  
12:10 I. Tsiaipkinis, Physical and numerical modeling of the Floating-Zone Process  
12:30 M. Kabukcuoglu, Evolution of dislocations and their behavior in GaAs wafers investigated by correlative X-ray diffraction imaging  
12:50 Closing Ceremony  
13:00 End of DKT2024  
14:00 Optional - Lab Tours

